



ElectroMagnetic Field(EMF) Radiation Exposure TEST REPORT

No. I22Z60151-SEM01

For

HONOR Device Co., Ltd.

Smart Phone

Model Name: LGE-NX9

with

Hardware Version: HN1LGEHM

Software Version: 6.0.0.108(C900E103R1P3)

FCC ID: 2AYGCLGE-NX9

Note:

The test results in this test report relate only to the devices specified in this report. This report shall not be reproduced except in full without the written approval of CTTL.

Test Laboratory:

CTTL, Telecommunication Technology Labs, CAICT

No. 51, Xueyuan Road, Haidian District, Beijing, P. R. China 100191.

Tel:+86(0)10-62304633-2512, Fax:+86(0)10-62304633-2504

Email: ctl_terminals@caict.ac.cn, website: www.caict.ac.cn

©Copyright. All rights reserved by CTTL.



Picture 1: Constituents of the sample



Picture A.1 Front side 10cm



Picture A.2 Rear side 10cm



Picture A.3 Left side 10cm



Picture A.4 Right side 10cm



Picture A.5 Top side 10cm



Picture A.6 Bottom side 10cm



Picture A.7 20% Charge amount



Picture A.8 50% Charge amount



Picture A.9 90% Charge amount